Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/670,587	BIAN, JINRU		
Examiner	Art Unit		
Gregory E. Webb	1751		

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
see attachment 2 pages	2/28/2006	GEW